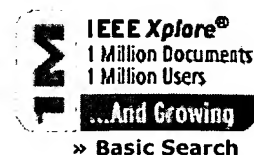


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radar In: All Fields

And

gauging In: All Fields

And

interference In: All Fields

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**1 Clutter and shadowed areas characterization of meteorological radars**  
*Gabella, M.; Ghigo, O.; Perona, G.;*  
Antennas and Propagation, Tenth International Conference on (Conf. Publ. No. 436) , Volume: 2 , 14-17 April 1997  
Pages:255 - 260 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(676 KB\)\]](#)   **IEE CNF**

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And

gauge In: Title

And

interference In: Title

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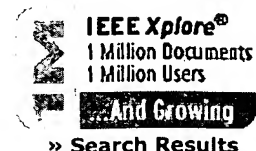
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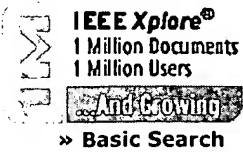
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radar In: Abstract

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gauge In: Abstract

And

interference In: Abstract

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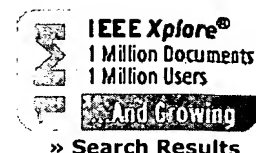
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